

General Description

The WSP4882 is the highest performance trench N-ch MOSFET with extreme high cell density, which provide excellent RDSON and gate chargens for most of the synchronous buck converter applications .

The WSP4882 meet the RoHS and Green Product requirement,100% EAS guaranteed with full function reliability approved.

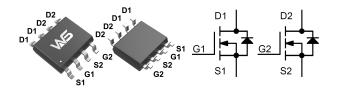
Product Summery

BVDSS	RDSON	ID
30V	20m Ω	8.0A

Application

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

SOP-8 Pin Configuration



Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	30	V
V _{GS}	Gate-Source Voltage	±20	V
I _D @T _C =25℃	Continuous Drain Current, V _{GS} @ 10V ¹	8.0	A
I _D @T _C =70℃	Continuous Drain Current, V _{GS} @ 10V ¹	7.0	A
I _{DM}	Pulsed Drain Current ²	40	A
EAS	Single Pulse Avalanche Energy ³	20	mJ
I _{AS}	Avalanche Current 9		A
P _D @T _A =25℃	Total Power Dissipation ⁴	2.0	W
T _{STG}	Storage Temperature Range -55 to 150		°C
TJ	Operating Junction Temperature Range -55 to 150		°C

Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
R _{θJA}	Thermal Resistance Junction-ambient ¹		90	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹		50	°C/W

Absolute Maximum Ratings



Dual N-Channel MOSFET

Electrical Characteristics (T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =250uA	30			V
$\triangle BV_{DSS} / \triangle T_J$	BVDSS Temperature Coefficient	Reference to 25 $^\circ\!\mathrm{C}$, I_D=1mA		0.034		V/℃
Б	Static Drain-Source On-Resistance ²	V _{GS} =10V , I _D =8A		20	26	
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =4.5V , I _D =5A		28	32	mΩ
V _{GS(th)}	Gate Threshold Voltage		1.5	1.8	2.5	V
	V _{GS(th)} Temperature Coefficient	$V_{GS}=V_{DS}$, $I_D=250$ uA		-5.8		mV/℃
		V _{DS} =24V , V _{GS} =0V , T _J =25°C			1	uA
I _{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}\text{=}24V$, $V_{\text{GS}}\text{=}0V$, $T_{\text{J}}\text{=}55^\circ\!\mathrm{C}$			5	
I _{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm20V$, $V_{DS}=0V$			±100	nA
gfs	Forward Transconductance	V _{DS} =5V , I _D =8A		6		S
R _g	Gate Resistance	V _{DS} =0V , V _{GS} =0V , f=1MHz		1.7	2.5	Ω
Qg	Total Gate Charge (4.5V)			6	8.4	nC
Q _{gs}	Gate-Source Charge	V _{DS} =15V , V _{GS} =4.5V , I _D =8A		1.5		
Q _{gd}	Gate-Drain Charge			2.5		
T _{d(on)}	Turn-On Delay Time			6	8.8	
Tr	Rise Time	V_{DD} =15V , V_{GEN} =10V , R_{G} =6 Ω		8.2	14	1
T _{d(off)}	Turn-Off Delay Time	I _D =1A,R∟=15Ω		16	6 24 ns	ns
T _f	Fall Time			4	8	1
C _{iss}	Input Capacitance	V _{DS} =15V , V _{GS} =0V , f=1MHz		580	701	
C _{oss}	Output Capacitance			95	112	pF
C _{rss}	Reverse Transfer Capacitance			57	91	

Guaranteed Avalanche Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
EAS	Single Pulse Avalanche Energy ⁵	V _{DD} =25V , L=0.5mH , I _{AS} =8A	18			mJ

Diode Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Is	Continuous Source Current ^{1,6}				2	А
I _{SM}	Pulsed Source Current ^{2,6}	$V_{G}=V_{D}=0V$, Force Current			40	А
V _{SD}	Diode Forward Voltage ²	V _{GS} =0V , I _S =1A , T _J =25℃			1.1	V
t _{rr}	Reverse Recovery Time			12		nS
Q _{rr}	Reverse Recovery Charge	IF=8A , dI/dt=100A/ μs , T _J =25 $^\circ C$		3.5		nC

Note :

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper,t<10sec.

2.The data tested by pulsed , pulse width \leq 300us , duty cycle \leq 2%

3.The EAS data shows Max. rating . The test condition is $V_{\text{DD}}\text{=}25\text{V}, V_{\text{GS}}\text{=}10\text{V}, \text{L=}0.5\text{mH}, \text{I}_{\text{AS}}\text{=}8\text{A}$

4.The power dissipation is limited by 150 $^\circ\!\!\mathbb{C}$ junction temperature

5. The Min. value is 100% EAS tested guarantee.

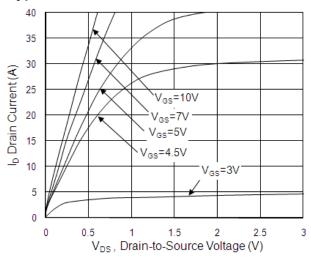
6.The data is theoretically the same as I_{D} and I_{DM} , in real applications , should be limited by total power dissipation.



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Typical Characteristics





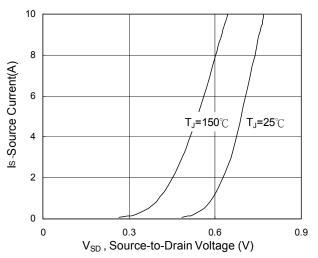
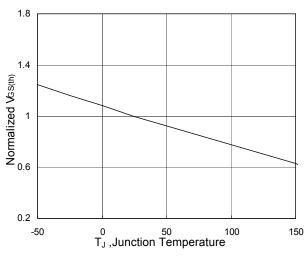


Fig.3 Forward Characteristics Of Reverse



 $(^{\circ}\!\mathrm{C})\text{\AA}ig.5$ Normalized $V_{GS(th)}$ vs. T_J

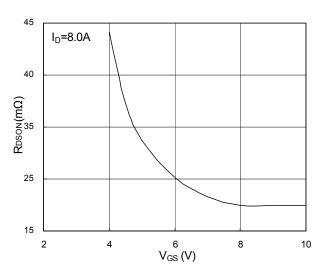


Fig.2 On-Resistance vs. G-S Voltage

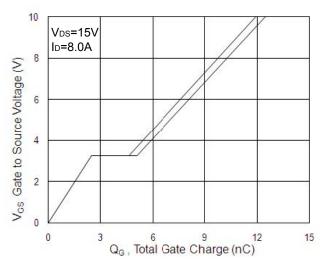
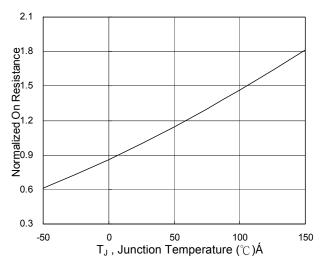
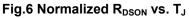


Fig.4 Gate-Charge Characteristics







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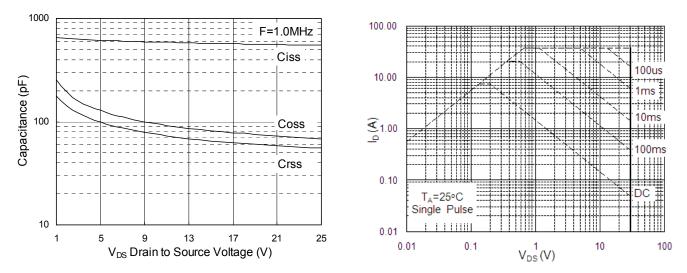
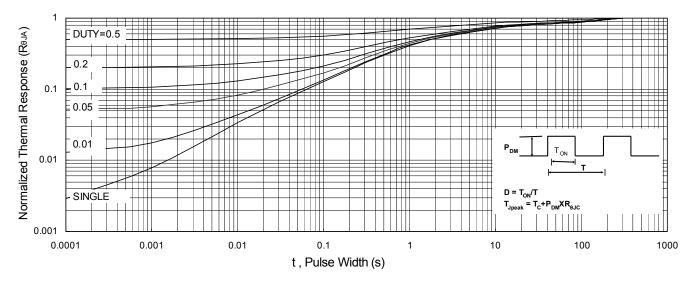
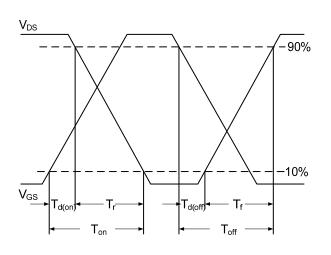


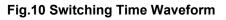
Fig.7 Capacitance

Fig.8 Safe Operating Area









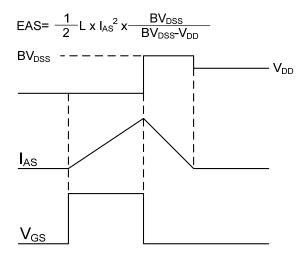


Fig.11 Unclamped Inductive Switching Waveform



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